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| Notice of References Cited | | Application/Control No. 10/571,467 | Applicant(s)/Patent Under Reexamination MISAWA ET AL. | |
| | | Examiner M. Lee | Art Unit 2622 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|------------------------|----------------|
| * | A | US-6,832,071 | 12-2004 | Nakamura et al. | 455/3.02 |
| * | B | US-5,301,352 | 04-1994 | Nakagawa et al. | 725/71 |
| * | C | US-5,959,592 | 09-1999 | Petruzzelli, Edmund F. | 725/68 |
| * | D | US-7,136,618 | 11-2006 | Kato et al. | 455/3.02 |
| * | E | US-4,672,687 | 06-1987 | Horton et al. | 455/150.1 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|-------------------------------------------------------------------------------------------|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

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